

Generic interconnect BIST for Network-on-Chip

Jutman, Artur; Ubar, Raimund-Johannes; Raik, Jaan DDECS : 8th IEEE Workshop on Design and Diagnostics of Electronic Circuits and Systems : April 13-16, 2005, Sopron, Hungary : proceedings 2005 / p. 224-227 : ill

An improved estimation technique for hybrid BIST test set generation

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